Se	Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/771,538	MIDORIKAWA ET AL.	
Examiner	Art Unit	-
Jean F. Duverne	2839	

SEARCHED			
Class	Subclass	Date	Examiner
439	74	4/10/2005	JFD /
	660		
	295		
	284		
	81		
	83		
	637	4/10/2005	JFD

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARC	H STRATEGY	<u>')</u>
	DATE	EXMR
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